

Date:- 23rd Oct 2001 Data Sheet Issue:- 1

Phase Control Thyristor Types N1010NC300 to N1010NC380

Absolute Maximum Ratings

	VOLTAGE RATINGS	MAXIMUM LIMITS	UNITS
V_{DRM}	Repetitive peak off-state voltage, (note 1)	3000-3800	V
V_{DSM}	Non-repetitive peak off-state voltage, (note 1)	3000-3800	V
V_{RRM}	Repetitive peak reverse voltage, (note 1)	3000-3800	V
V_{RSM}	Non-repetitive peak reverse voltage, (note 1)	3100-3900	V

	OTHER RATINGS	MAXIMUM LIMITS	UNITS
$I_{T(AV)}$	Mean on-state current. T _{sink} =55°C, (note 2)	1010	Α
$I_{T(AV)}$	Mean on-state current. T _{sink} =85°C, (note 2)	704	Α
$I_{T(AV)}$	Mean on-state current. T _{sink} =85°C, (note 3)	436	Α
I _{T(RMS)}	Nominal RMS on-state current. T _{sink} =25°C, (note 2)	1978	Α
I _{T(d.c.)}	D.C. on-state current. T _{sink} =25°C, (note 4)	1754	Α
I _{TSM}	Peak non-repetitive surge t _p =10ms, V _{rm} =0.6V _{RRM} , (note 5)	12100	Α
I _{TSM2}	Peak non-repetitive surge t _p =10ms, V _{rm} ≤10V, (note 5)	13300	Α
l ² t	I ² t capacity for fusing t _p =10ms, V _{rm} =0.6V _{RRM} , (note 5)	732×10 ³	A ² s
l ² t	I²t capacity for fusing t _p =10ms, V _{rm} ≤10V, (note 5)	884×10 ³	A ² s
al: /al#	Maximum rate of rise of on-state current (repetitive), (Note 6)	200	A/µs
di _⊤ /dt	Maximum rate of rise of on-state current (non-repetitive), (Note 6)	400	A/µs
V_{RGM}	Peak reverse gate voltage	5	V
$P_{G(AV)}$	Mean forward gate power	4	W
P_{GM}	Peak forward gate power	30	W
V_{GD}	Non-trigger gate voltage, (Note 7)	0.25	V
T _{HS}	Operating temperature range	-40 to +125	°C
T_{stg}	Storage temperature range	-40 to +150	°C

Notes: -

- 1) De-rating factor of 0.13% per °C is applicable for T_j below 25°C.
- 2) Double side cooled, single phase; 50Hz, 180° half-sinewave.
- 3) Single side cooled, single phase; 50Hz, 180° half-sinewave.
- Double side cooled.
- 5) Half-sinewave, 125°C T_i initial.
- 6) V_D =67% V_{DRM} , I_{TM} =1000A, I_{FG} =2A, t_r ≤0.5 μ s, T_{case} =125°C.
- 7) Rated V_{DRM} .

Characteristics

	PARAMETER	MIN.	TYP.	MAX.	TEST CONDITIONS (Note 1)	UNITS
V_{TM}	Maximum peak on-state voltage	-	-	2.43	I _{TM} =1830A	V
V_0	Threshold voltage	-	-	1.17		V
r _S	Slope resistance	-	-	0.687		mΩ
dv/dt	Critical rate of rise of off-state voltage	200	-	-	V _D =80% V _{DRM} , linear ramp, Gate O/C	V/μs
I _{DRM}	Peak off-state current	-	-	100	Rated V _{DRM}	mA
I _{RRM}	Peak reverse current	-	-	100	Rated V _{RRM}	mA
V_{GT}	Gate trigger voltage	-	-	3.0	T 0500 W 40W 1 0A	V
I _{GT}	Gate trigger current	-	-	300	T_j =25°C, V_D =10V, I_T =2A	mA
I _H	Holding current	-	-	1000	T _j =25°C	mA
t _{gd}	Gate controlled turn-on delay time	-	1.0	1.5	V _D =67%V _{DRM} , I _{TM} =1000A,	
t _{gt}	Turn-on time	-	2.5	3.0	di/dt=20A/ μ s, I _{FG} =2A, t _r =0.5 μ s, T _i =25°C	μs
Q _{rr}	Recovered Charge	-	4800	-		μC
Q _{ra}	Recovered Charge, 50% chord	-	2000	2500	I _{TM} =1000A, t _p =1000μs, di/dt=10A/μs,	μC
I _{rm}	Reverse recovery current	-	125	-	V _r =50V	Α
t _{rr}	Reverse recovery time, 50% chord	-	32	-		μs
4	Turn-off time	-	600	650	I_{TM} =1000A, t_p =1000 μ s, di/dt=10A/ μ s, V_r =50V, V_{dr} =80% V_{DRM} , dV_{dr} /dt=20V/ μ s	
t _q	Turn-on time	-	1100	1200	I_{TM} =1000A, t_p =1000 μ s, di/dt=10A/ μ s, V_r =50V, V_{dr} =80% V_{DRM} , dV_{dr} /dt=200V/ μ s	μs
D	Thermal registance, junction to heatsink	-	-	0.024	Double side cooled	K/W
$R_{th(j-hs)}$	Thermal resistance, junction to heatsink	-	-	0.048	Single side cooled	K/W
F	Mounting force	19	-	29		kN
W_t	Weight	-	510	-		g

Notes: -

1) Unless otherwise indicated T_j =125°C.

Notes on Ratings and Characteristics

1.0 Voltage Grade Table

Voltage Grade	V _{DRM} V _{DSM} V _{RRM} V	V _{RSM} V	V _D V _R DC V
30	3000	3100	1750
32	3200	3300	1800
34	3400	3500	1850
36	3600	3700	1900
38	3800	3900	1950

2.0 Extension of Voltage Grades

This report is applicable to other and higher voltage grades when supply has been agreed by Sales/Production.

3.0 De-rating Factor

A blocking voltage de-rating factor of 0.13%/°C is applicable to this device for T_i below 25°C.

4.0 Repetitive dv/dt

Standard dv/dt is 1000V/µs.

5.0 Rate of rise of on-state current

The maximum un-primed rate of rise of on-state current must not exceed 400A/µs at any time during turnon on a non-repetitive basis. For repetitive performance, the on-state rate of rise of current must not exceed 200A/us at any time during turn-on. Note that these values of rate of rise of current apply to the total device current including that from any local snubber network.

6.0 Gate Drive

The recommended pulse gate drive is 30V, 15Ω with a short-circuit current rise time of not more than 0.5µs. This gate drive must be applied when using the full di/dt capability of the device.

The pulse duration may need to be configured according to the application but should be no shorter than 20µs, otherwise an increase in pulse current may be needed to supply the necessary charge to trigger.

7.0 Computer Modelling Parameters

7.1 Device Dissipation Calculations

7.1 Device Dissipation Calculations
$$I_{AV} = \frac{-V_0 + \sqrt{{V_0}^2 + 4 \cdot f f^2 \cdot r_s \cdot W_{AV}}}{2 \cdot f f^2 \cdot r_s} \qquad \text{and:} \qquad W_{AV} = \frac{\Delta T}{R_{th}} \\ \Delta T = T_{j\,\text{max}} - T_{Hs}$$

Where $V_0=1.17V$, $r_s=0.687m\Omega$,

 R_{th} = Supplementary thermal impedance, see table below.

ff = Form factor, see table below.

Supplementary Thermal Impedance									
Conduction Angle	30°	60°	90°	120°	180°	270°	d.c.		
Square wave Double Side Cooled	0.03047	0.03035	0.02857	0.02733	0.02569	0.0242	0.024		
Square wave Single Side Cooled	0.05823	0.0577	0.05408	0.05286	0.05121	0.0497	0.048		
Sine wave Double Side Cooled 0.0303 0.0275 0.0262 0.02524 0.024									
Sine wave Single Side Cooled	0.05588	0.05323	0.05186	0.05089	0.048				

Form Factors									
Conduction Angle	30°	60°	90°	120°	180°	270°	d.c.		
Square wave	3.46	2.45	2	1.73	1.41	1.15	1		
Sine wave	3.98	2.78	2.22	1.88	1.57				

7.2 Calculating V_T using ABCD Coefficients

The on-state characteristic I_T vs. V_T , on page 5 is represented in two ways;

- the well established V₀ and r_s tangent used for rating purposes and (i)
- (ii) a set of constants A, B, C, D, forming the coefficients of the representative equation for V_T in terms of I_T given below:

$$V_T = A + B \cdot \ln(I_T) + C \cdot I_T + D \cdot \sqrt{I_T}$$

The constants, derived by curve fitting software, are given below for both hot and cold characteristics. The resulting values for V_T agree with the true device characteristic over a current range, which is limited to that plotted.

	25°C Coefficients		125°C Coefficients
Α	0.9538873	Α	0.571466615
В	B 0.07518263		0.1223907
С	C 4.912747×10 ⁻⁴		7.111703×10 ⁻⁴
D	-2.98×10 ⁻³	D	-8.46958×10 ⁻³

7.3 D.C. Thermal Impedance Calculation

$$r_t = \sum_{p=1}^{p=n} r_p \cdot \left(1 - e^{\frac{-t}{\tau_p}}\right)$$

Where p = 1 to n, n is the number of terms in the series and:

t =Duration of heating pulse in seconds.

r, =Thermal resistance at time t.

rp =Amplitude of pth term.

τ_p =Time Constant of r_{th} term

D.C. Double Side Cooled									
Term	Term 1 2 3 4 5								
r_p	0.01248	6.216×10 ⁻³	1.939×10 ⁻³	1.527×10 ⁻³	1.038×10 ⁻³				
$ au_{\mathcal{D}}$	0.884	0.1221	0.03612	7.612×10 ⁻³	1.93×10 ⁻³				

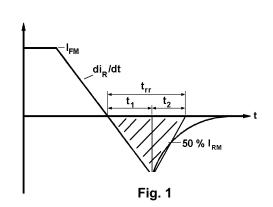
D.C. Single Side Cooled										
Term	Term 1 2 3 4 5 6 7									
r_{p}	0.02836	5.574×10 ⁻³	3.588×10 ⁻³	6.222×10 ⁻³	2.04×10 ⁻³	1.675×10 ⁻³	1.258×10 ⁻³			
$ au_{\mathcal{P}}$	6.345	3.55	0.582	0.132	0.0496	0.01015	2.225×10 ⁻³			

8.0 Reverse recovery ratings

- (i) Qra is based on 50% Irm chord as shown in Fig. 1.
- (ii) Q_{rr} is based on a 150μs integration time.

i.e.
$$Q_{rr} = \int_{0}^{150 \, \mu s} i_{rr}.dt$$
 $K \ Factor = \frac{t_1}{t_2}$

(iii)
$$K Factor = \frac{t_1}{t_2}$$



Curves

Figure 1 - On-state characteristics of Limit device

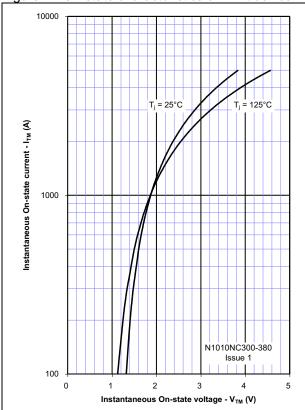


Figure 2 - Transient Thermal Impedance

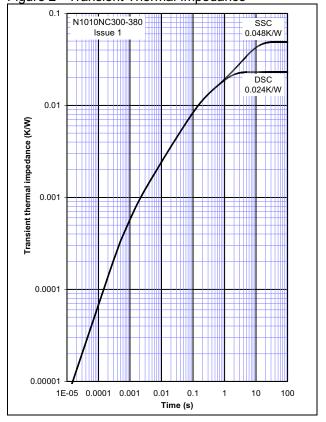


Figure 3 - Gate Characteristics - Trigger Limits

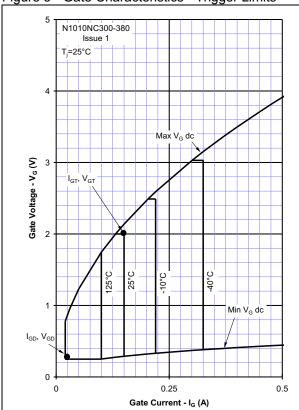
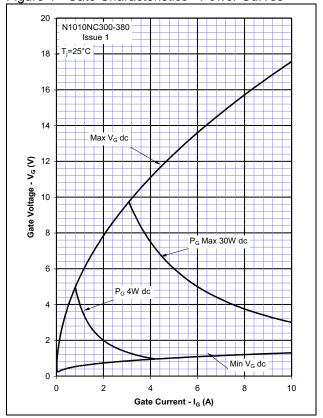
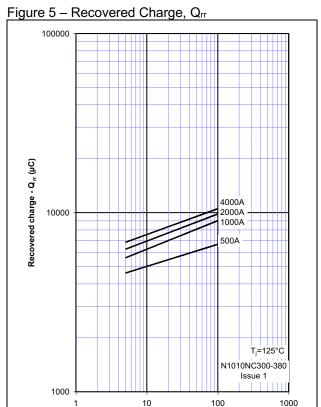


Figure 4 - Gate Characteristics - Power Curves





di/dt (A/µs)

Figure 6 – Recovered charge, Q_{ra} (50% chord)

10000

10000

10000

10000

10000

10000

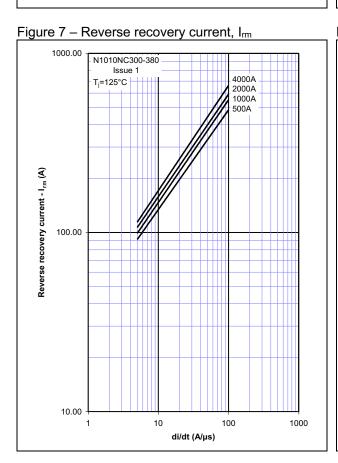
10000

10000

10000

10000

di/dt (A/µs)



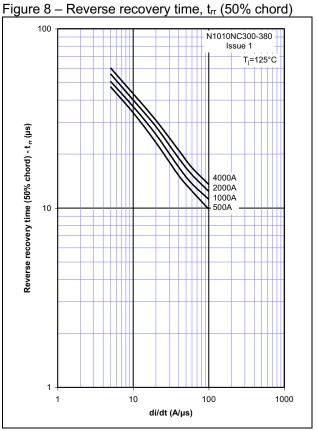


Figure 9 – On-state current vs. Power dissipation – Double Side Cooled (Sine wave)

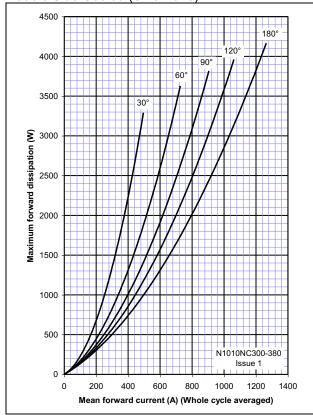


Figure 10 – On-state current vs. Heatsink temperature - Double Side Cooled (Sine wave)

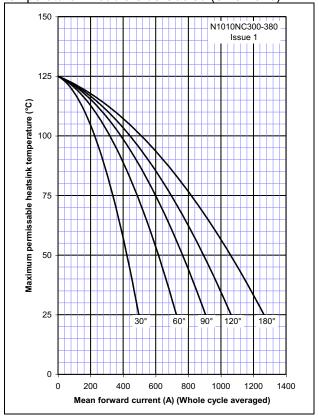


Figure 11 – On-state current vs. Power dissipation – Double Side Cooled (Square wave)

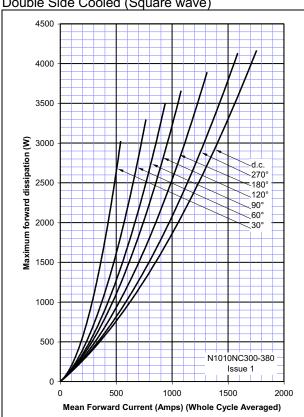


Figure 12 – On-state current vs. Heatsink temperature - Double Side Cooled (Square wave)

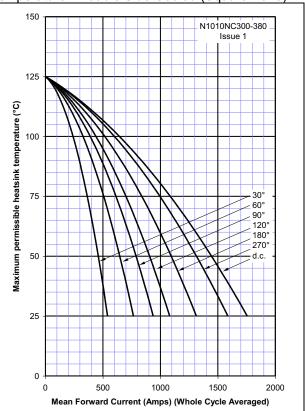


Figure 13 – On-state current vs. Power dissipation – Single Side Cooled (Sine wave)

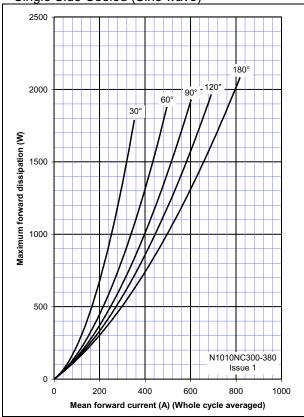


Figure 15 – On-state current vs. Power dissipation – Single Side Cooled (Square wave)

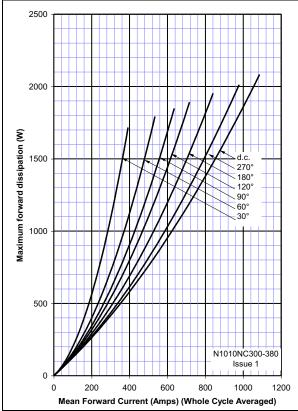


Figure 14 – On-state current vs. Heatsink temperature - Single Side Cooled (Sine wave)

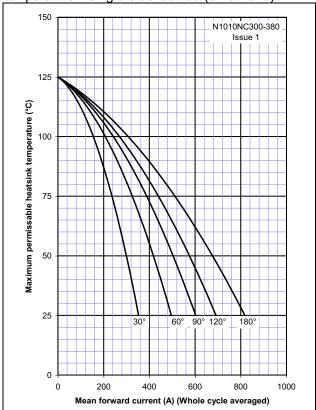
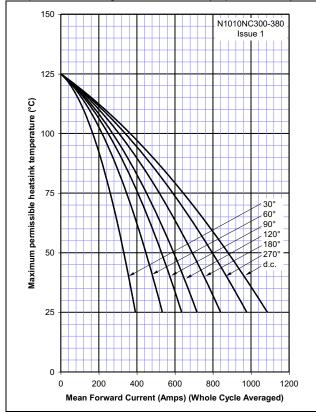
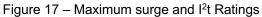
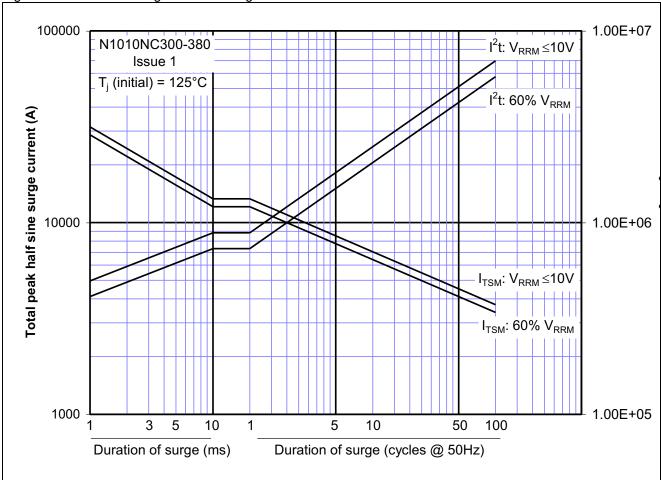
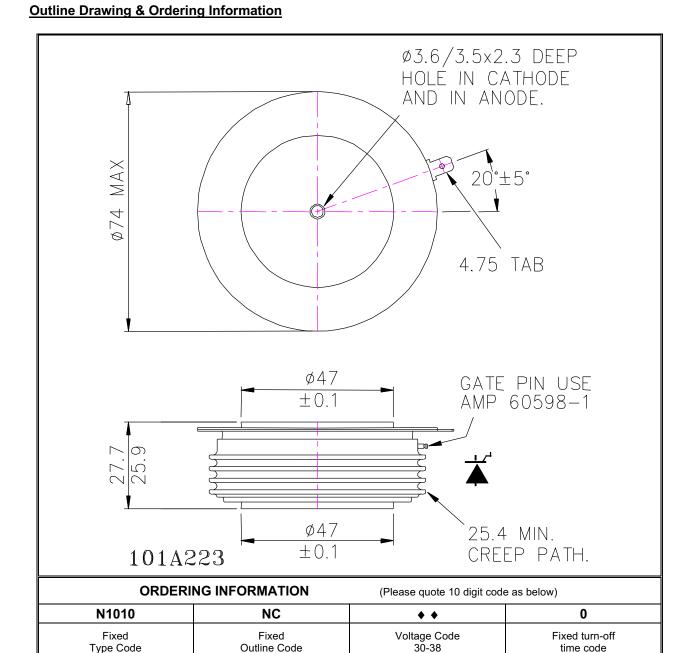


Figure 16 – On-state current vs. Heatsink temperature - Single Side Cooled (Square wave)









Typical order code: N1010NC320 – 3200V V_{DRM}/V_{RRM}, 27.7mm clamp height capsule.

WESTCODE

UK: Westcode Semiconductors Ltd. P.O. Box 57, Chippenham, Wiltshire, England. SN15 1JL. Tel: +44 (0) 1249 444524 Fax: +44 (0) 1249 659448 E-Mail: WSL.sales@westcode.com

USA: Westcode Semiconductors Inc. 3270 Cherry Avenue, Long Beach, California 90807 Tel: +1 (562) 595 6971 Fax: +1 (562) 595 8182

E-Mail: WSI.sales@westcode.com

Internet: http://www.westcode.com

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